

**Search Notes**

Application/Control No.

10/534,275

Examiner

Daniel Lai

Applicant(s)/Patent under  
Reexamination

HOSHINO ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
455	69 70 506	4/21/2007	DL
455	504 505	4/27/2007	DL
455	63.4 226.3	4/27/2007	DL
455	522	4/27/2007	DL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference Search Printout		4/27/2007	DL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Keyword search (see search history)	4/21/2007	DL
limited class/subclass search (see search history)	4/21/2007	DL
Consulted with SPE for search help	4/21/2007	DL
Consulted with SPE for allowance	4/26/2007	DL